## Notice of References Cited Application/Control No. 10/733,980 Applicant(s)/Patent Under Reexamination HWU ET AL. Examiner Victor V Yevsikov Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	А	US-2003/0211743 A1	11-2003	Chang et al.	438/692
	В	US-2004/0166686 A1	08-2004	Lin et al.	438/692
	С	US-6,300,248 B1	10-2001	Lin et al.	438/692
	D	US-6,303,507 B1	10-2001	Wang et al.	438/692
	E	US-2003/0124856 A1	07-2003	Kneer, Emil A.	438/692
	F	US-2003/0064594 A1	04-2003	Delage et al.	438/691
	G	US-6,586,336 B2	07-2003	Jeong, In Kwon	438/692
	Н	US-2002/0197872 A1	12-2002	Hollatz et al.	438/692
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name ·	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
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	w			
	X			

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